

# DM7420

## Dual 4-Input NAND Gate

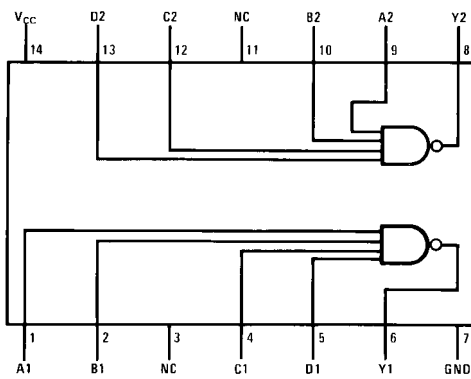
### General Description

This device contains two independent gates each of which performs the logic NAND function.

### Ordering Code:

Order Number	Package Number	Package Description
DM7420N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

### Connection Diagram



### Function Table

$$Y = \overline{ABCD}$$

Inputs				Output
A	B	C	D	Y
X	X	X	L	H
X	X	L	X	H
X	L	X	X	H
L	X	X	X	H
H	H	H	H	L

H = HIGH Logic Level  
L = LOW Logic Level  
X = Either LOW or HIGH Logic Level

**Absolute Maximum Ratings** (Note 1)

Supply Voltage	7V
Input Voltage	5.5V
Operating Free Air Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +150°C

**Note 1:** The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

**Recommended Operating Conditions**

Symbol	Parameter	Min	Nom	Max	Units
V <sub>CC</sub>	Supply Voltage	4.75	5	5.25	V
V <sub>IH</sub>	HIGH Level Input Voltage	2			V
V <sub>IL</sub>	LOW Level Input Voltage			0.8	V
I <sub>OH</sub>	HIGH Level Output Current			-0.4	mA
I <sub>OL</sub>	LOW Level Output Current			16	mA
T <sub>A</sub>	Free Air Operating Temperature	0		70	°C

**Electrical Characteristics**

over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 2)	Max	Units
V <sub>I</sub>	Input Clamp Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA			-1.5	V
V <sub>OH</sub>	HIGH Level Output Voltage	V <sub>CC</sub> = Min, I <sub>OH</sub> = Max V <sub>IL</sub> = Max	2.4	3.4		V
V <sub>OL</sub>	LOW Level Output Voltage	V <sub>CC</sub> = Min, I <sub>OL</sub> = Max V <sub>IH</sub> = Min		0.2	0.4	V
I <sub>I</sub>	Input Current @ Max Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5V			1	mA
I <sub>IH</sub>	HIGH Level Input Current	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4V			40	μA
I <sub>IL</sub>	LOW Level Input Current	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4V			-1.6	mA
I <sub>OS</sub>	Short Circuit Output Current	V <sub>CC</sub> = Max (Note 3)	-18		-55	mA
I <sub>CCH</sub>	Supply Current with Outputs HIGH	V <sub>CC</sub> = Max		2	4	mA
I <sub>CCL</sub>	Supply Current with Outputs LOW	V <sub>CC</sub> = Max		6	11	mA

**Note 2:** All typicals are at V<sub>CC</sub> = 5V, T<sub>A</sub> = 25°C.

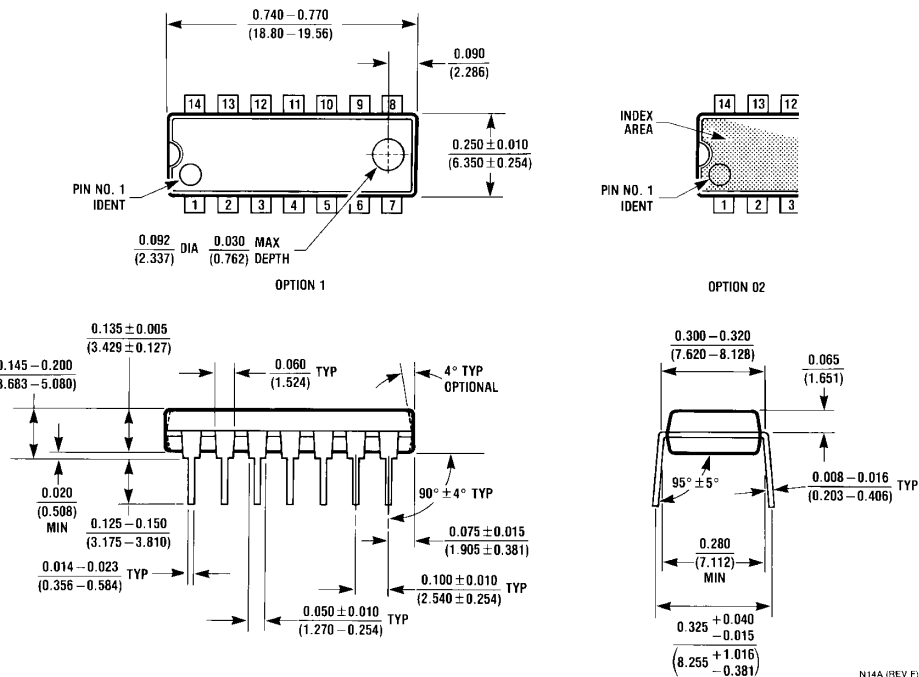
**Note 3:** Not more than one output should be shorted at a time.

**Switching Characteristics**

at V<sub>CC</sub> = 5V and T<sub>A</sub> = 25°C

Symbol	Parameter	Conditions	Min	Max	Units
t <sub>PLH</sub>	Propagation Delay Time LOW-to-HIGH Level Output	C <sub>L</sub> = 15 pF R <sub>L</sub> = 400Ω		22	ns
t <sub>PHL</sub>	Propagation Delay Time HIGH-to-LOW Level Output			15	ns

**Physical Dimensions** inches (millimeters) unless otherwise noted



**14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A**

N14A (REV F)

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